

<b>Notice of References Cited</b>		Application/Control No. 10/582,788	Applicant(s)/Patent Under Reexamination ONO ET AL.	
		Examiner John L. Goff	Art Unit 1791	Page 1 of 1

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	U	Machine translation of JP 2001348786 date unknown
	V	Machine translation of JP 06106682 date unknown
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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